



INFORMATION DISCLOSURE STATEMENT

Applicants : Aydogan Ozcan et al.
App. No : 10/645,331
Filed : August 21, 2003
For : METHOD OF MEASURING A
PHYSICAL FUNCTION USING A
COMPOSITE FUNCTION WHICH
INCLUDES THE PHYSICAL
FUNCTION AND AN ARBITRARY
REFERENCE FUNCTION
Examiner : Sang H. Nguyen
Art Unit : 2877

CERTIFICATE OF MAILING

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

6/15/05

(Date)

Bruce S. Itchkawitz, Reg. No. 47,677

Mail Stop Amendment

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Enclosed for filing in the above-identified application is a PTO/SB/08 Equivalent listing twenty-seven (27) references to be considered by the Examiner. Also enclosed are ten (10) non-patent literature references as listed on the Information Disclosure Statement.

This Information Disclosure Statement is being filed before the mailing date of a final action and before the mailing of a Notice of Allowance. This Statement is accompanied by the fees set forth in 37 C.F.R. § 1.17(p). The Commissioner is hereby authorized to charge any additional fees which may be required or to credit any overpayment to Account No. 11-1410.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: _____

6/15/05

By: _____

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Application No. 10/645,331
 Filing Date August 21, 2003
 First Named Inventor Aydogan Ozcan
 Art Unit 2877
 Examiner Sang H. Nguyen
 Attorney Docket No. STANF.131CP2

(Multiple sheets used when necessary)

SHEET 1 OF 2

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	3,880,630	04/29/1975	Izawa	
	2	4,985,178	01/15/1991	Tam	
	3	5,086,239	02/04/1992	Wang	
	4	5,194,918	03/16/1993	Kino et al.	
	5	5,220,451	06/15/1993	Gotoh et al.	
	6	5,239,407	08/24/1993	Brueck et al.	
	7	5,247,601	09/21/1993	Myers et al.	
	8	5,262,890	11/16/1993	Berkovic et al.	
	9	5,368,782	11/29/1994	Gotoh et al.	
	10	5,420,717	05/30/1995	Tabata	
	11	5,434,699	07/18/1995	Berkovic et al.	
	12	5,523,840	06/06/1996	Nishizawa et al.	
	13	5,615,041	03/25/1997	Field et al.	
	14	6,043,884	03/28/2000	Curbelo	
	15	6,856,393 B2	02/15/2005	Ozcan et al. (Atty. Docket No. STANF.131CP1)	
	16	2004/0036880 A1	02/26/2004	Ozcan et al. (Atty. Docket No. STANF.131A)	
	17	2004/0044714 A1	03/04/2004	Ozcan et al. (Atty. Docket No. STANF.131CP1)	

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ¹
	18	Fienup, J.R., "Reconstruction of an object from the modulus of its Fourier transform," <u>Optics Letters</u> , Vol. 3, No. 1, July 1978, pp. 27-29.	
	19	Ozcan, A., et al., "A simple post-processing technique to improve the retrieval accuracy of second-order nonlinearity profiles," Edward L. Ginzton Laboratory: Stanford University, Stanford, California 94305; ©2004 Optical Society of America, 2 pages.	
	20	Ozcan, A., et al., "Cylinder-assisted Maker-fringe Technique," <u>Electronics Letters</u> , Vol. 39, No. 25, 11 th December 2003, 2 pages.	

Examiner Signature

Date Considered

***Examiner:** Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

T¹ - Place a check mark in this area when an English language Translation is attached.

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	Filing Date	August 21, 2003
	First Named Inventor	Aydogan Ozcan
	Art Unit	2877
(Multiple sheets used when necessary)	Examiner	Sang H. Nguyen
SHEET 2 OF 2	Attorney Docket No.	STANF.131CP2

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ¹
	21	Ozcan, A., et al., "Improved Fourier transform technique to determine second-order optical nonlinearity profiles," Edward L. Ginzton Laboratory: Stanford University, Stanford, California 94305; ©2003 Optical Society of America, 3 pages.	
	22	Ozcan, A., et al., "Improved technique to determine second-order optical nonlinearity profiles using two different samples," <u>Applied Physics Letters</u> , Vol. 84, No. 5, 2 February 2004, pp. 681-683.	
	23	Ozcan, A., et al., Erratum: "Inverse Fourier transform technique to determine second-order optical nonlinearity spatial profiles," <u>Applied Physics Letters</u> , Vol. 83, No. 8, 25 August 2003, p. 1679.	
	24	Ozcan, A., et al., "Post-processing of the second-order optical nonlinearity profile of thin films," Edward L. Ginzton Laboratory: Stanford University, Stanford, California 94305; ©2004 Optical Society of America, 2 pages.	
	25	Ozcan, A., et al., "Simplified inverse Fourier transform technique to determine second-order optical nonlinearity profiles using a reference sample," <u>Electronics Letters</u> , Vol. 40, No. 9, 29 th April 2004, 2 pages.	
	26	Quatieri, Thomas F., Jr., et al., "Iterative techniques for minimum phase signal reconstruction from phase or magnitude," <u>IEEE Trans. Acoust. Speech, Signal Processing</u> , Vol. 29, 1981, pp. 1187-1193.	
	27	Rosenthal, Amir, et al., "Inverse Scattering Algorithm for Reconstructing Strongly Reflecting Fiber Bragg Gratings," <u>IEEE Journal of Quantum Electronics</u> , Vol. 39, No. 8, August 2003, pp. 1018-1026.	

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